## Search Notes Application/Control No. Applicant(s)/Patent Under Reexamination AKHAPKINA ET AL. Examiner Kim, Jennifer Art Unit 1617

SEARCHED					
Class	Subclass	Date	Examiner		
514	408, 545	3/15/2007	jmk		
	Updated	7/30/2007	jmk		
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SEARCH NOTES					
Search Notes	Date	Examiner			
Registry; inventor search; international search report; chemdraw	3/15/2007	jmk			
Updated; STN (registry) see serach terms.	7/30/2007	jmk			
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